

AON3806



Common-Drain Dual N-Channel Enhancement Mode Field Effect Transistor

General Description

The AON3806/L uses advanced trench technology to provide excellent $R_{\rm DS(ON)}$, low gate charge and operation with gate voltages as low as 2.5V while retaining a 12V $V_{\rm GS(MAX)}$ rating. It is ESD protected. This device is suitable for use as a uni-directional or bi-directional load switch, facilitated by its commondrain configuration. AON3806 and AON3806L are electrically identical.

- -RoHS Compliant
- -AO3806L is Halogen Free

Features

 $V_{DS}(V) = 20V$

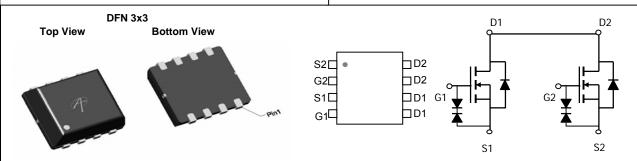
 $I_D = 6.8 \text{ A } (V_{GS} = 4.5 \text{V})$

 $R_{DS(ON)}$ < 26m Ω (V_{GS} = 4.5V)

 $R_{DS(ON)}$ < 27m Ω (V_{GS} = 4V)

 $R_{DS(ON)}$ < 35m Ω (V_{GS} = 2.5V)

ESD Protected



Absolute Maximum Ratings T _A =25°C unless otherwise noted							
Parameter		Symbol	Maximum	Units			
Drain-Source Voltage		V _{DS}	20	V			
Gate-Source Voltage		V_{GS}	±12	V			
Continuous Drain	T _A =25°C		6.8				
Current ^A	T _A =70°C	I _D	5.4	A			
Pulsed Drain Current ^B		I _{DM}	40	7			
	T _A =25°C	В	1.9	W			
Power Dissipation ^A	T _A =70°C	$-P_D$	1.2	T vv			
Junction and Storage Temperature Range		T _J , T _{STG}	-55 to 150	°C			

Thermal Characteristics								
Parameter	Symbol	Тур	Max	Units				
Maximum Junction-to-Ambient A	t ≤ 10s	$R_{ hetaJA}$	55	65	°C/W			
Maximum Junction-to-Ambient A	Steady-State	Γ _θ JA	78	95	°C/W			
Maximum Junction-to-Lead ^C	Steady-State	$R_{\theta JL}$	30	50	°C/W			

Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions		Min	Тур	Max	Units		
STATIC PARAMETERS									
BV_{DSS}	Drain-Source Breakdown Voltage	I _D =250μA, V _{GS} =0V		20			V		
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =16V, V _{GS} =0V				1			
			T _J =55°C			5	μА		
I_{GSS}	Gate-Body leakage current	V _{DS} =0V, V _{GS} =±10V				10	μА		
BV_{GSO}	Gate-Source Breakdown Voltage	V _{DS} =0V, I _G =±250uA		±12			V		
$V_{GS(th)}$	Gate Threshold Voltage	V _{DS} =V _{GS} I _D =250μA		0.5	0.7	1	V		
$I_{D(ON)}$	On state drain current	V _{GS} =4.5V, V _{DS} =5V		40			Α		
R _{DS(ON)}	Static Drain-Source On-Resistance	V _{GS} =4.5V, I _D =6.8A		16	21	26	mΩ		
			T _J =125°C	22	29	35			
		V _{GS} =4V, I _D =6A		17	22	27	mΩ		
		V _{GS} =2.5V, I _D =5A		22	28	35	mΩ		
g _{FS}	Forward Transconductance	V _{DS} =5V, I _D =6.8A			25		S		
V_{SD}	Diode Forward Voltage	I _S =1A,V _{GS} =0V			0.75	1	V		
I _S	Maximum Body-Diode Continuous Current					2.5	Α		
DYNAMIC	PARAMETERS								
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =10V, f=1MHz			615		pF		
Coss	Output Capacitance				150		pF		
C _{rss}	Reverse Transfer Capacitance				120		pF		
R_g	Gate resistance	V _{GS} =0V, V _{DS} =0V, f=1MHz			1.2		Ω		
SWITCHII	NG PARAMETERS								
Q_g	Total Gate Charge	V _{GS} =4.5V, V _{DS} =10V, I _D =6.8A			8.5		nC		
Q_{gs}	Gate Source Charge				1.2		nC		
Q_{gd}	Gate Drain Charge				3		nC		
t _{D(on)}	Turn-On DelayTime				7		ns		
t _r	Turn-On Rise Time	V_{GS} =5V, V_{DS} =10V, R_L =1.4 Ω , R_{GEN} =3 Ω			13		ns		
$t_{D(off)}$	Turn-Off DelayTime				29		ns		
t _f	Turn-Off Fall Time				11		ns		
t _{rr}	Body Diode Reverse Recovery Time	I _F =6.8A, dI/dt=100A/μs			15		ns		
Q _{rr}	Body Diode Reverse Recovery Charge	I _F =6.8A, dI/dt=100A/μs			5		nC		

A: The value of R $_{0JA}$ is measured with the device mounted on 1in 2 FR-4 board with 2oz. Copper, in a still air environment with T $_A$ =25°C.

Rev 5: Feb. 2008

THIS PRODUCT HAS BEEN DESIGNED AND QUALIFIED FOR THE CONSUMER MARKET. APPLICATIONS OR USES AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS ARE NOT AUTHORIZED. AOS DOES NOT ASSUME ANY LIABILITY ARISING OUT OF SUCH APPLICATIONS OR USES OF ITS PRODUCTS. AOS RESERVES THE RIGHT TO IMPROVE PRODUCT DESIGN, FUNCTIONS AND RELIABILITY WITHOUT NOTICE.

The value in any given application depends on the user's specific board design. The current rating is based on the t \leq 10s thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C. The R $_{\theta JA}$ is the sum of the thermal impedence from junction to lead R $_{\theta JL}$ and lead to ambient.

D. The static characteristics in Figures 1 to 6,12,14 are obtained using <300 µs pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in ² FR-4 board with 2oz. Copper, in a still air environment with T _A=25°C. The SOA curve provides a single pulse rating.

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

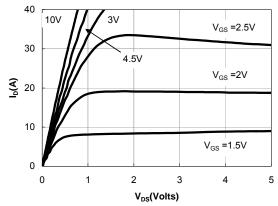


Figure 1: On-Regions CharacteristiCS

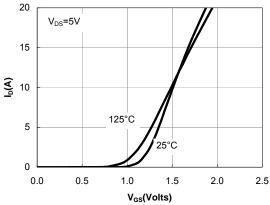


Figure 2: Transfer Characteristics

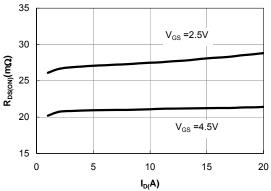


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

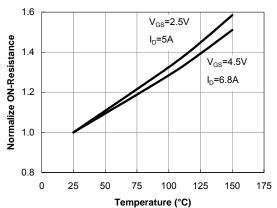


Figure 4: On-Resistance vs. Junction Temperature

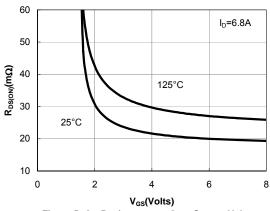


Figure 5: On-Resistance vs. Gate-Source Voltage

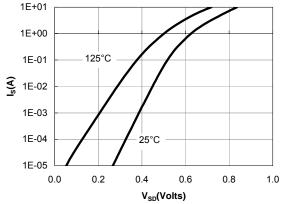


Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

